

● **Features**

$V_{DS} = -100V,$

$I_D = -0.9A$

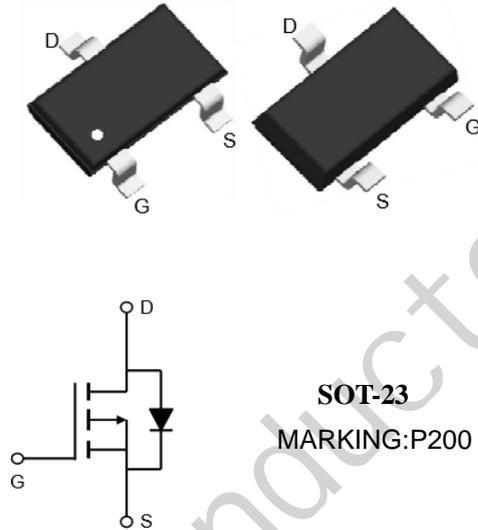
$R_{DS(ON)} @V_{GS} = -10V, TYP 470m\Omega$

$R_{DS(ON)} @V_{GS} = -4.5V, TYP 520m\Omega$

● **General Description**

- Super Low Gate Charge
- Excellent Cdv/dt effect decline

● **Pin Configurations**



● **Absolute Maximum Ratings @ $T_A=25^\circ C$  unless otherwise noted**

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage		$V_{DSS}$	100	V
Gate-Source Voltage		$V_{GSS}$	$\pm 20$	V
Drain Current (Continuous) *AC	$T_A=25^\circ C$	$I_D$	-0.9	A
	$T_A=70^\circ C$		-0.7	
Drain Current (Pulse) *B		$I_{DM}$	-1.8	A
Power Dissipation	$T_A=25^\circ C$	$P_D$	1	W
Operating Temperature/ Storage Temperature		$T_J/T_{STG}$	-55~150	$^\circ C$

● **Thermal Resistance Ratings**

Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient	$t \leq 5s$	$R_{thJA}$	100	125	$^\circ C/W$

● **Electrical Characteristics** @ $T_A=25^\circ\text{C}$  unless otherwise noted

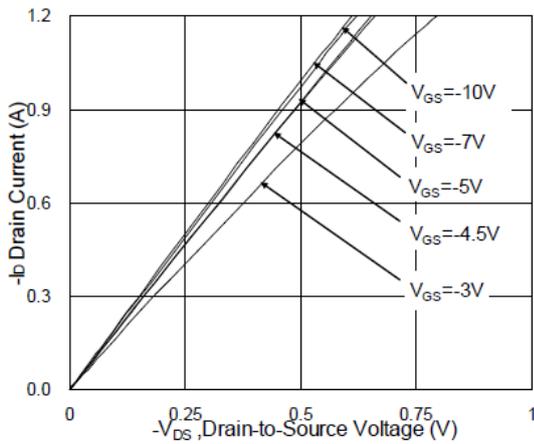
Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
<b>Static</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu A$	-100	--	--	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -80V, V_{GS} = 0V$	--	--	-10	$\mu A$
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_{DS} = -250\mu A$	-1	-2	-3	V
Gate Leakage Current	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$	--	--	$\pm 100$	nA
Drain-Source On-state Resistance	$R_{DS(on)}$	$V_{GS} = -10V, I_D = -0.8A$	--	470	650	m $\Omega$
	$R_{DS(on)}$	$V_{GS} = -4.5V, I_D = -0.4A$	--	520	700	m $\Omega$
Forward Transconductance	$g_{FS}$	$V_{DS} = -5V, I_D = -0.8A$	--	3	--	S
Diode Forward Voltage	$V_{SD}$	$I_{SD} = -1A, V_{GS} = 0V$	--	--	-1.2	V
Diode Forward Current	$I_S$	$T_C = 25^\circ\text{C}$	--	--	-0.9	A
<b>Switching</b>						
Total Gate Charge	$Q_g$	$V_{GS} = -4.5V, V_{DS} = -15V,$ $I_D = -0.5A$	--	4.5	--	nC
Gate-Source Charge	$Q_{gs}$		--	1.14	--	nC
Gate-Drain Charge	$Q_{gd}$		--	1.5	--	nC
Turn-on Delay Time	$t_{d(on)}$	$V_{DS} = -50V, I_D = -0.5A$ $R_G = 3.3\Omega, V_{GS} = -10V$	--	13.6	--	ns
Turn-on Rise Time	$t_r$		--	6.8	--	ns
Turn-off Delay Time	$t_{d(off)}$		--	34	--	ns
Turn-Off Fall Time	$t_f$		--	3	--	ns
<b>Dynamic</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = -15V, f = 1.0\text{MHz}$	--	553	--	pF
Output Capacitance	$C_{oss}$		--	29	--	pF
Reverse Transfer Capacitance	$C_{rss}$		--	20	--	pF

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

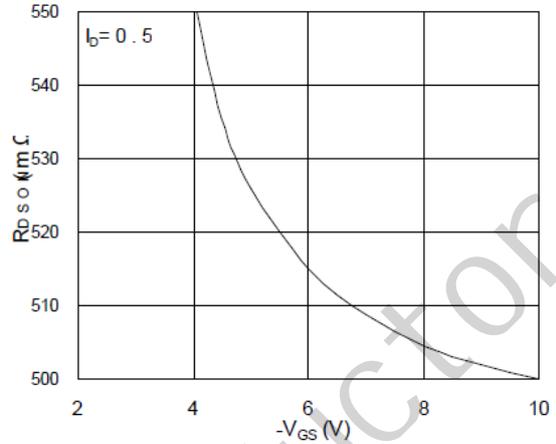
B: Repetitive rating, pulse width limited by junction temperature.

C: The current rating is based on the  $\leq 10\text{s}$  junction to ambient thermal resistance rating.

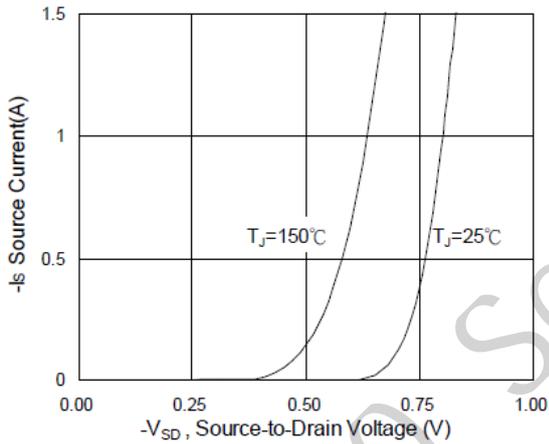
● Typical Performance Characteristics (T<sub>J</sub> = 25 °C, unless otherwise noted)



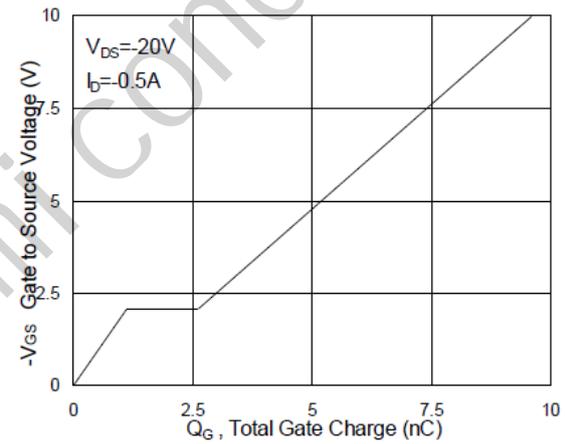
Output Characteristics



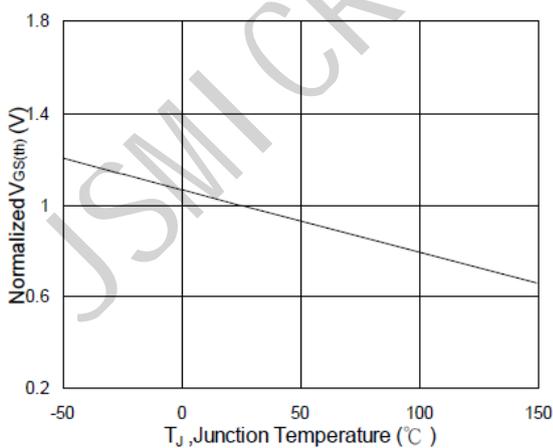
On-Resistance vs. Gate-to-Source Voltage



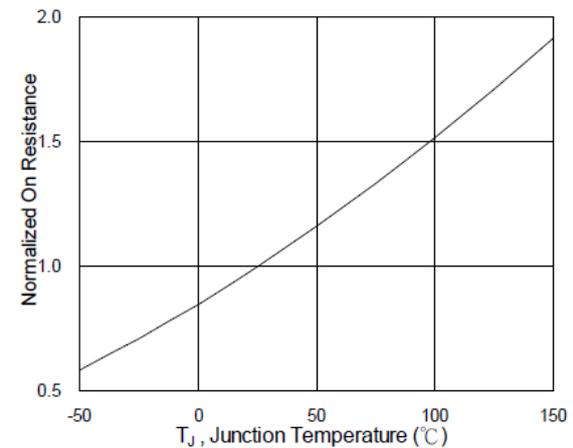
Source-Drain Diode Forward Voltage



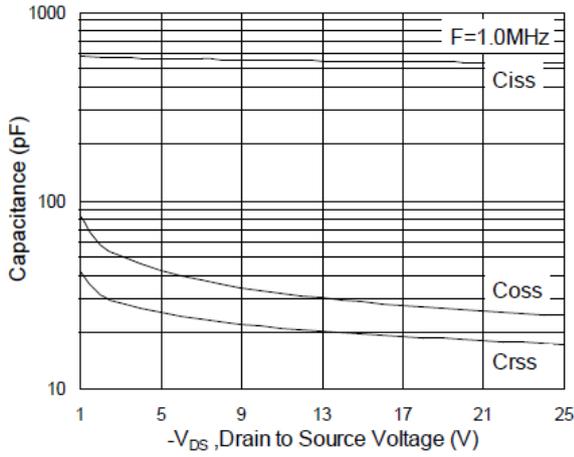
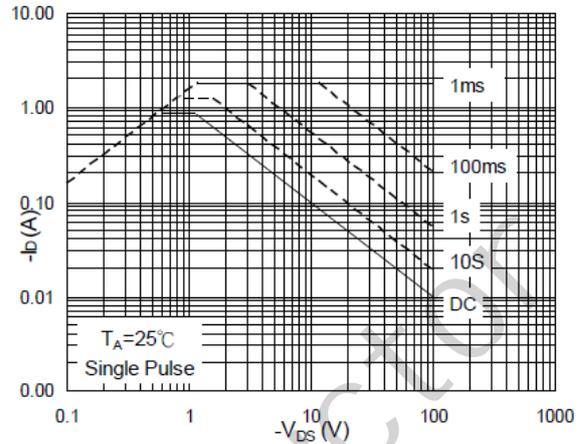
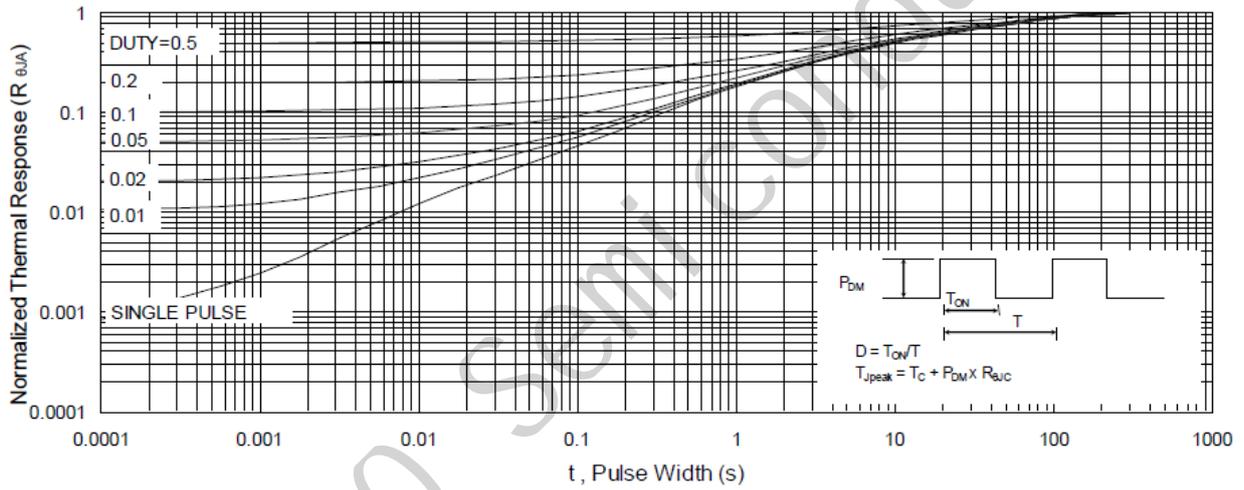
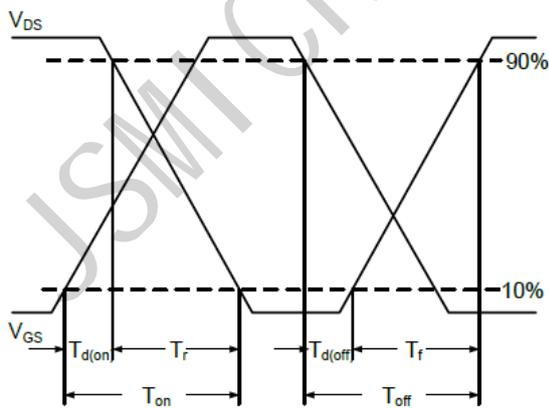
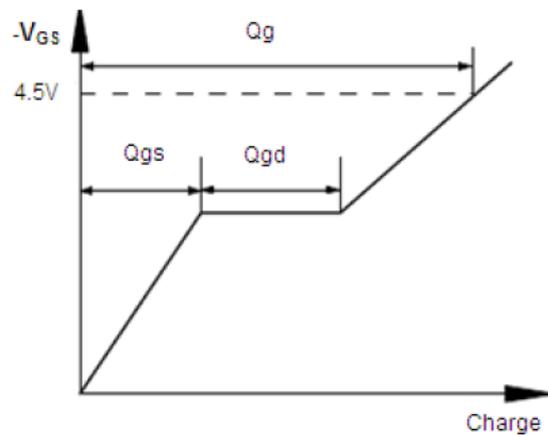
Gate Charge



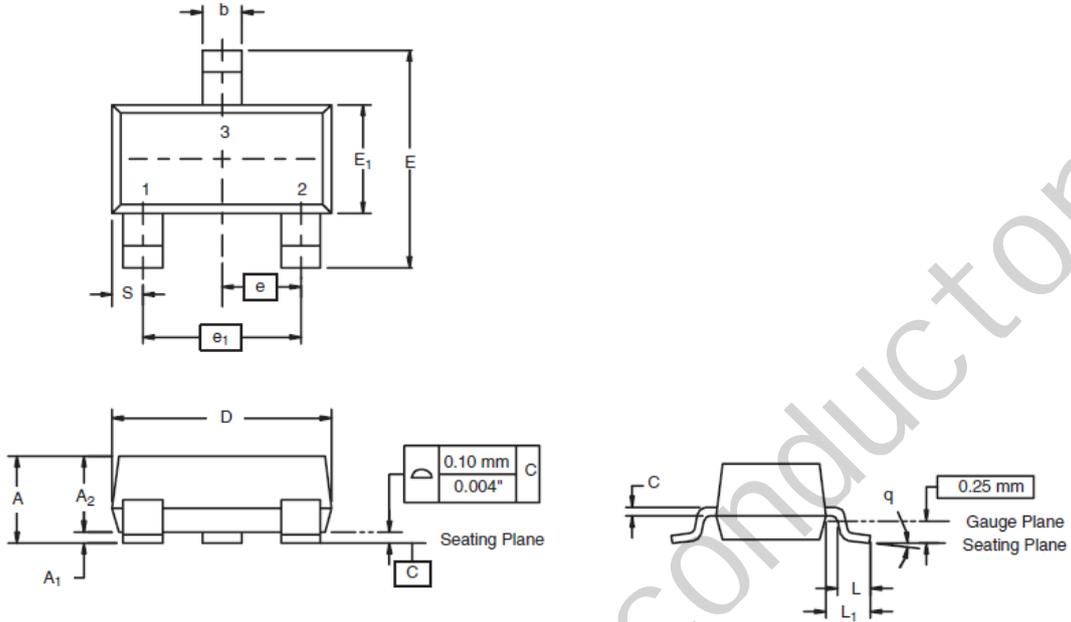
Threshold Voltage



On-Resistance vs. Junction Temperature


**Capacitance**

**Safe Operating Area**

**Normalized Thermal Transient Impedance, Junction-to-Ambient**

**Switching Time Waveforms**

**Gate Charge Waveform**

## ● Package Information



Dim	MILLIMETERS		INCHES	
	Min	Max	Min	Max
A	0.89	1.12	0.035	0.044
A <sub>1</sub>	0.01	0.10	0.0004	0.004
A <sub>2</sub>	0.88	1.02	0.0346	0.040
b	0.35	0.50	0.014	0.020
c	0.085	0.18	0.003	0.007
D	2.80	3.04	0.110	0.120
E	2.10	2.64	0.083	0.104
E <sub>1</sub>	1.20	1.40	0.047	0.055
e	0.95 BSC		0.0374 Ref	
e <sub>1</sub>	1.90 BSC		0.0748 Ref	
L	0.40	0.60	0.016	0.024
L <sub>1</sub>	0.64 Ref		0.025 Ref	
S	0.50 Ref		0.020 Ref	
q	3°	8°	3°	8°